



Exclusive
10% discount
on styli and
probes!

// INVITATION

ZEISS User Meeting 2018 Singapore

17 April 2018, Tuesday
9:00 AM - 3:30 PM

ZEISS Competence Centre
Level 1, 50 Kaki Bukit Place
Singapore 415926
[> Map](#)



ZEISS User Meeting 2018 Singapore

See the New ZEISS DotScan on an ACCURA at this User Meeting

ZEISS warmly invites you to this year's User Meeting held at the newly renovated ZEISS Competence Centre.

Open to all users, this User Meeting introduces the capabilities and benefits of the market's first white light sensor on an articulating probe holder - the ZEISS DotScan. Adding on to that, we will also talk about the latest updates on the ZEISS CALYPSO Software and available training courses provided by ZEISS.

Finally, exclusive to attendees of the User Meeting, we will be offering a 10% discount on styli and probe purchases during the event day only. We hope to see you soon and talk about how to further your successes in metrology!

Agenda

Time	Activity
9:00 AM	Registration
9:30 AM	ZEISS CALYPSO 6.4 - New Functions
10:30 AM	ZEISS PiWeb
11:30 AM	New Training Courses: <ul style="list-style-type: none">■ AUKOM■ GD&T■ Measurement Strategies: Cookbook
12:30 PM	Lunch
1:30 PM	ZEISS DotScan Presentation and Demonstration
3:00 PM	Announcement and Inquiries
3:15 PM	Quiz Challenge
3:30 PM	End of User Meeting 2018 Singapore

Cost

Free

Registration

Reservation of seats are handled online only.

For inquiries, please contact Mr. Rajdave Sidhu
Mobile: +65 9674 7309 // rajdave.sidhu@zeiss.com

Highlights of the User Meeting

- Experience the new Competence Centre
- LIVE demo of ZEISS DotScan on ACCURA
- 10% savings on styli and probes
- Introduction of AUKOM Training by ZEISS
- New ZEISS give-aways to attendees

[Click here to register!](#)

The moment you can count on reliable results even before measuring.

This is the moment we work for.

www.zeiss.com.sg/metrology

More Light on the Subject

ZEISS launches the first adjustable chromatic white light sensor

Chromatic white light sensors enable the non-contact capture of workpiece topography. These are generally used when sensitive, reflective or poor-contrast surfaces make it difficult to use other optical sensors. This is the first white light sensor on an articulating probe holder available on the market. During the measuring run, it can be exchanged for other contact or optical sensors.

See it LIVE in action with the ZEISS ACCURA at this year's Singapore User Meeting. Save your seat today!



[> More on ZEISS DotScan](#)